

# HM-7620/21

# HIGH SPEED 512 x 4 PROM

HM-7620- Open Collector Outputs HM-7621 - "Three State" Outputs

#### Features

FAST ADDRESS ACCESS TIME

HM-7620/21	•		٠	٠				٠		70 ns MAXIMUM
HM-7620A/21A										50 ns MAXIMUM
HM-7620B/21B										40 ns MAXIMUM

- "THREE STATE" OR OPEN COLLECTOR OUTPUTS AND A SINGLE CHIP ENABLE INPUT
- SIMPLE HIGH SPEED PROGRAMMING PROCEDURE-ONE PULSE/BIT ASSURES FAST PROGRAMMING AND SUPERIOR RELIABILITY.
- INPUTS AND OUTPUTS TTL COMPATIBLE
- FAST ACCESS TIME—GUARANTEED FOR WORST CASE N<sup>2</sup> SEQUENC-ING OVER COMMERCIAL AND MILITARY TEMPERATURE AND VOLT— AGE RANGES.
- PIN COMPATIBLE WITH INDUSTRY STANDARD 2K PROMs.

# Description

The HM-7620/21 are fully decoded high speed Schottky TTL 2048 bit Field Programmable ROM's in a 512 word by 4 bit/word format with open collector (HM-7620) or "three state" (HM-7621) outputs. These PROMs are available in 16 pin D.I.P. (ceramic or power plastic).

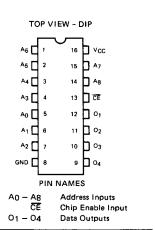
All bits are manufactured storing a logical "1" (positive logic) and can be selectively programmed for a logical "0" in any bit position.

The HM-7620/21 contain test rows and columns which are in addition to the storage array to assure high programmability and guarantee parametric and A. C. performance. The fuses in these test rows and columns are blown prior to shipment.

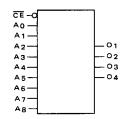
This PROM is intended for use in state of the art high speed logic systems. Nickel-chromium fuse technology is used on these and all other Harris Bipolar PROMs.

There is a single chip enable input on the HM-7620/21 where  $\overline{\text{CE}}$  low enables the chip.

## Pinout



# Logic Symbol



Functional Diagram (14)(15) 1 OF 32 32 x 64 (1) MEMORY ADDRESS DECODER (2) BUFFERS ARRAY 10 (3) (4) 16 16 16 16 (7) 1 OF 16 TRANS-TRANS-TRANS-TRANS-COLUMN COLUMN (6) MISSION MISSION MISSION MISSION ADDRESS DECODER GATES GATES GATES GATES BUFFERS (5) CHIP 4 OUTPUT BUFFERS (13)ENABLE LOGIC () = PIN NUMBERS (16) = VCC (12) (11)(10)(B) = GND

# Specifications HM-7620/21

## ABSOLUTE MAXIMUM RATINGS

Output or Supply Voltage (Operating) -0.3 to +7.0V Storage Temperature -65°C to +150°C Address/Enable Input Voltage Operating Temperature (Ambient) -55°C to +125°C Address/Enable Input Current -20mA Maximum Junction Temperature +175°C Output Sink Current 100mA

CAUTION: Stresses above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied. (While programming, follow the programming specifications.)

D.C. ELECTRICAL CHARACTERISTICS (Operating) HM-7620/21-5 ( $V_{CC} = 5.0V \pm 5\%$ ,  $T_A = 0^{\circ}C$  to +75°C) HM-7620/21-2/-8 ( $V_{CC} = 5.0V \pm 10\%$ ,  $T_A = -55^{\circ}C$  to +125°C) Typical measurements are at TA = 25°C, VCC = +5V. NOTE: Multiple entries refer to parameter values for "A", "B"/Std.

Positive current defined as into device terminals.

SYMBOL	PARAMET	ER	MIN	TYP	MAX	UNITS	TEST CONDITIONS
lih lit	Address/enable Input Current	"1" "0"	_	-	+40 -100/-250	μA μA	VIH = VCC Max. VIL = 0.45V
VIH VIL	Input Threshold Voltage	"1"	2.0* -	_	0.8*	<b>V</b>	VCC = VCC Min. VCC = VCC Max.
VOH VOL	Output Voltage	"1"	2.4 **	3.2 * * 0.35	_ 0.50	V V	IOH = -2.0mA, VCC = VCC Min. IOL = +16mA, VCC = VCC Min.
IOHE IOLE	Output Disable Current	"1"	_	=	+40/+100 -40/-100**	μΑ μΑ	VOH, VCC = VCC Max. VOL = 0.3V, VCC = VCC Max.
VCL	Input Clamp Vol	tage		_	-1.2	٧	IIN = -18mA
los	Output Short Circ Current	cuit	-15**	-	-100**	mA	VCC = VCC Max. VOUT = 0.0V One Output Only for a Max. of 1 Second
ICC	Power Supply Cu	rrent	-	90	120/130	mA	VCC = VCC Max. All Inputs Grounded

<sup>\*</sup> These are absolute voltages with respect to ground pin and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.

## A.C. ELECTRICAL CHARACTERISTICS (Operating)

Typical Measurements are at TA = 25°C, VCC = +5V.

	HM-7620/21 · 5 5V ±5% 0°C to +75°C							HM-7620/21-2/8 5V <u>+</u> 10% -55°C to +125°C						
		"[	в"	"	Α"	S	TD	"1	3"	,	۹"	s.	ro	
SYMBOL	PARAMETER	TYP	MAX	TYP	MAX	TYP	MAX	TYP	MAX	TYP	MAX	TYP	MAX	UNITS
TAA TEA TDA	Address Access Time Chip Enable Access Time Chip Disable Access Time		40 25 25	40 - -	50 25 25	50 - -	70 25 25	-	55 30 30		70 30 30	_ _ _	85 30 30	ns ns ns

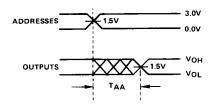
A.C. limits guaranteed for worst case N2 sequencing with maximum test frequency of 5MHz,

CAPACITANCE: TA = 25°C

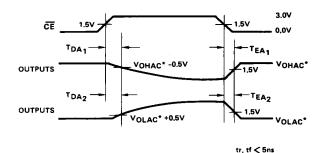
SYMBOL	PARAMETER	TYPICAL	UNITS	TEST CONDITIONS
CINA, CINCE	Input Capacitance	8	pF	VCC = 5V, VIN = 2.0V, f = 1MHz
COUT	Output Capacitance	10	pF	VCC = 5V, VOUT = 2.0V, f = 1MHz

<sup>\*\* &</sup>quot;Three-State" only.

# HM-7620/21 SWITCHING TIME DEFINITIONS

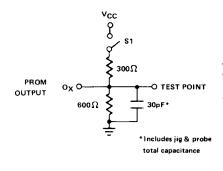


NOTE: As is common to all memory devices, output levels can be undefined during the address access period (TAA); however, the outputs are guaranteed to reach stable levels by TAA. It is not recommended that outputs from this class of devices be used to drive edge triggered inputs on subsequent devices (counters, flip-flops, etc.) without proper intermediate synchronization.



\*VOLAC AND VOHAC ARE THE MEASURED OUTPUT VOLTAGE LEVELS WHILE ENABLED.

#### A.C. TEST LOAD



This is the A.C. Test Load which Harris Semiconductor uses in its automatic test equipment, and it is recommended that users of Harris bipolar devices use the same or an equivalent load in performing A.C. testing.

SYMBOL	PARAMETER	S1
TAA	Address Access Time	Closed
*TEA1	Chip Enable Access Time from "Three State" to VOH	Open
T <sub>EA2</sub>	Chip Enable Access Time to VOL	Closed
*TDA1	Chip Disable Access Time from VOH to "Three State"	Open
T <sub>DA2</sub>	Chip Disable Access Time from VOL	Closed

\*Applies to "Three-State" only.